

10

## WHAT IS CLAIMED IS:

- 1. A chemical-mechanical polishing system comprising:
  - (a) a liquid carrier,
  - (b) a polishing pad and/or an abrasive, and
  - (c) at least one amine-containing polymer with about 5 or more sequential atoms separating the nitrogen atoms of the amino functional groups.
- 2. The system of claim 1, wherein at least one amine-containing polymer is a condensation polymer comprising repeating units that contain an amino functional group.
- 3. The system of claim 2, wherein the condensation polymer is a polyaminoamide.
- 4. The system of claim 3, wherein the condensation polymer is a diethylenetriamine/adipic acid condensation polymer.
- 5. The system of claim 1, wherein at least one amine-containing polymer is polydiallyldimethylammonium chloride.
- 6. The system of claim 1, wherein at least one amine-containing polymer is a copolymer comprising repeating units containing an amine functional group and repeating units selected from the group consisting of amides, vinyl acetate, ethylene oxide, and propylene oxide.
- 7. The system of claim 1, wherein at least one amine-containing polymer has about 7 or more sequential atoms separating the nitrogen atoms of the amino functional groups.



- 8. The system of claim 1, wherein at least one amine-containing polymer has about 10 or more sequential atoms separating the nitrogen atoms of the amino functional groups.
  - 9. The system of claim 1, further comprising a per-type oxidizer.
- 10. The system of claim 9, wherein the per-type oxidizer is selected from the group consisting of peroxides, persulfates, periodates, and permanganates.
  - 11. The system of claim 1, further comprising a complexing agent.
  - 12. A chemical-mechanical polishing system comprising:
    - (a) a liquid carrier,
    - (b) a polishing pad and/or an abrasive, and
    - (c) at least one amine-containing block copolymer with at least one polymer block comprising one or more amine functional groups and at least one polymer block not comprising any amine functional groups.
- 13. The system of claim 12, wherein at least one amine-containing block copolymer is an AB diblock, ABA triblock, or ABC triblock copolymer.
- 14. The system of claim 12, wherein the polymer blocks comprising one or more amine functional groups are about 10 wt.% or more of the amine-containing block copolymer.
- 15. The system of claim 14, wherein the polymer blocks comprising one or more amine functional groups are about 20 wt.% or more of the amine-containing block copolymer.





16. The system of claim 12, wherein the polymer block comprising one or more amine functional groups are about 40 wt.% or more of the amine-containing block copolymer.

12

- 17. The system of claim 12, wherein at least one amine-containing block has about 5 or more sequential atoms separating the nitrogen atoms of the amino functional groups.
  - 18. A method of polishing one or more layers of a multi-layer substrate comprising:
    - (i) providing a substrate comprising a first metal-containing layer and a second layer, wherein the first and second layers are not the same,
    - (ii) providing a chemical-mechanical polishing system comprising:
      - (a) a liquid carrier,
      - (b) a polishing pad and/or an abrasive, and
      - (c) at least one amine-containing polymer that is (1) an amine-containing polymer with at least 5 or more sequential atoms separating the nitrogen atoms of the amino functional groups or (2) an amine-containing block copolymer with at least one polymer block comprising one or more amine functional groups and at least one polymer block not comprising any amine functional groups,
    - (iii) contacting the substrate with the chemical-mechanical polishing system, and
    - (iv) abrading at least a portion of the substrate to polish the substrate.
- 19. The method of claim 18, wherein the first metal-containing layer comprises copper, tantalum, titanium, or tungsten.
- 20. The method of claim 18, wherein the first metal-containing layer comprises a noble metal selected from the group consisting of platinum, iridium, rhenium, ruthenium, rhodium, palladium, silver, osmium and gold.



- 21. The method of claim 20, wherein the noble metal is platinum.
- 22. The method of claim 20, wherein the noble metal is iridium.
- 23. The method of claim 20, wherein the noble metal is ruthenium.
- 24. The method of claim 18, wherein the second layer comprises a metal oxide.